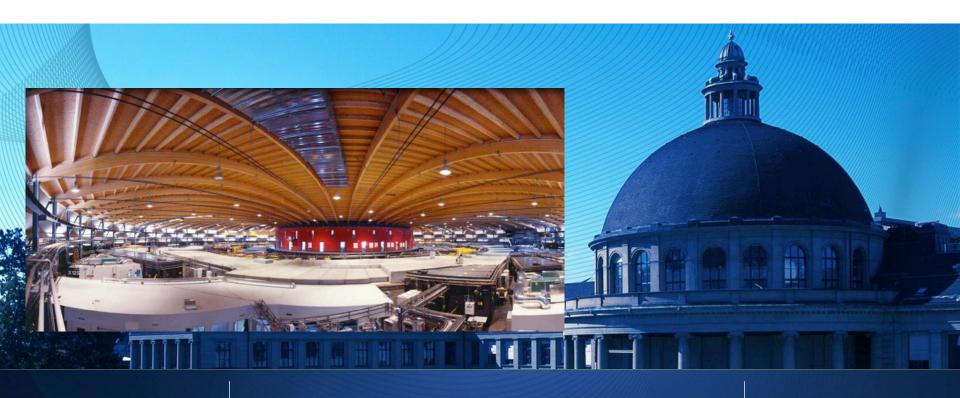




Dark field and transmission in the Compton regime

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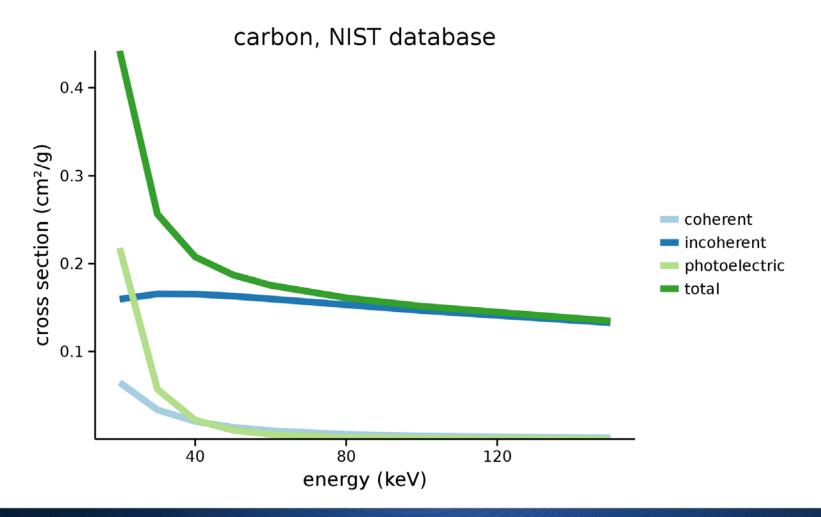






What is the Compton regime?

Energy > 40-50 keV for biomedical applications







Signals from phase stepping curves

- Moduli of the first two Fourier coefficients a_0 , a_1
- Transmission $A = \frac{a_{0,s}}{a_{0,f}}$
- Dark field $B = \frac{a_{1,S}}{a_{1,f}} \frac{a_{0,f}}{a_{0,S}}$
- Ratio $R = \frac{\log B}{\log A}$





The ratio R in literature below 40 kVp

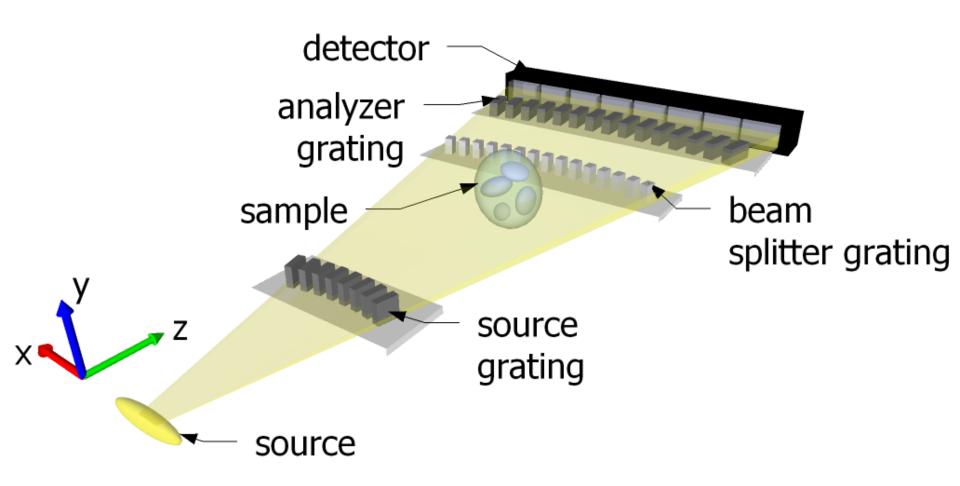
- Independent of thickness
- Depends on atomic number
- Depends on microstructure size

Wang and Stampanoni, Quantitative x-ray radiography using grating interferometry: a feasibility study, Phys. Med. Biol., 2013 Scherer et al., Non-invasive Differentiation of Kidney Stone Types using X-ray Dark-Field Radiography, Sci. Rep., 2015





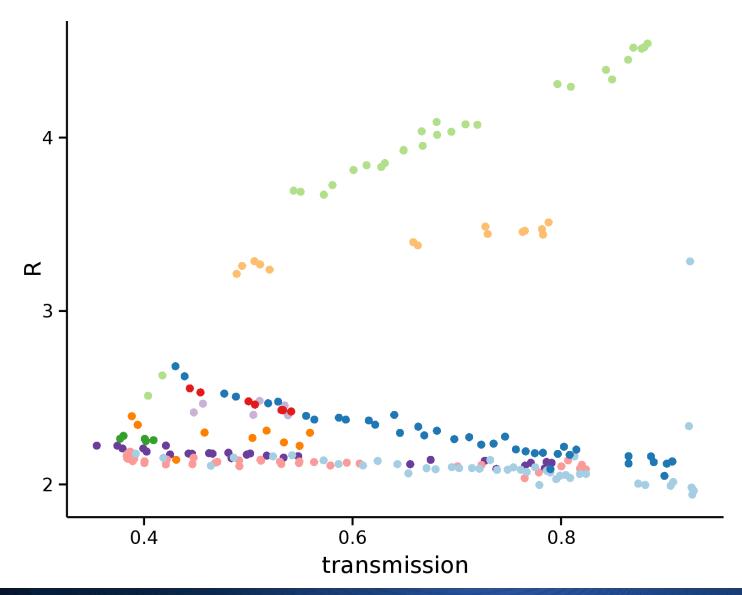
Edge-on illumination for experiments at 160 kVp







Experiment at 160 kVp



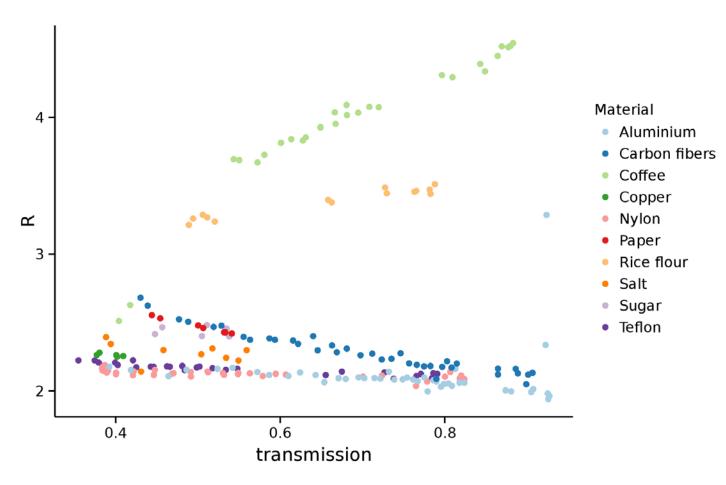
Material

- Aluminium
- Carbon fibers
- Coffee
- Copper
- Nylon
- Paper
- Rice flour
- Salt
- Sugar
- Teflon





Experiment at 160 kVp



- R independent of thickness
- R depends on atomic number
- R depends on microstructures





No Z information

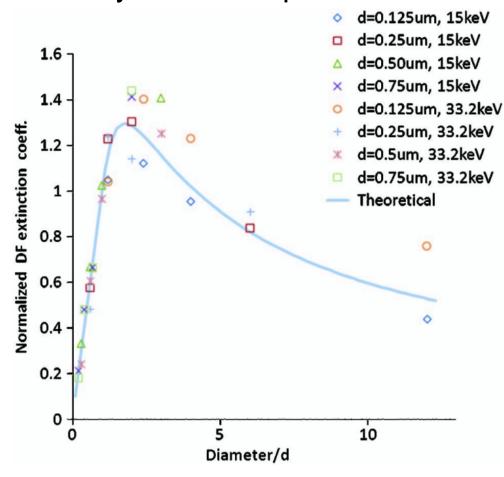
- Given by photoelectric absorption $\propto Z^{3-4}$
- Irrelevant above 50 keV for low-Z materials





Microstructures

 Lynch et al. 2011, synchrotron experiment and analytical description



$$\mu_{
m d} = rac{3\pi^2}{\lambda^2} f |\Delta\chi|^2 d egin{cases} D' - \sqrt{D'^2 - 1} (1 + D'^{-2}/2) + \ (D'^{-1} - D'^{-3}/4) \ & \ln[(D' + \sqrt{D'^2 - 1})/ \ (D' - \sqrt{D'^2 - 1})], & ext{for } D > d; \ D', & ext{for } D \leq d; \end{cases}$$

$$\mu_d = \frac{-\log B}{t} = R\mu$$





Microstructures on polychromatic sources

- Compute the contribution as in Lynch et al for each energy → R(E)
- Sum over spectral weights w(E)
- Our model, with 2 parameters R₀ and C:

$$R = R_0 + C \sum_{E} w(E)R(E)$$





Spectral weights

 $w(E) = \text{source} \times \text{visibility} \times \text{detector efficiency} \times \text{sample abs.}$

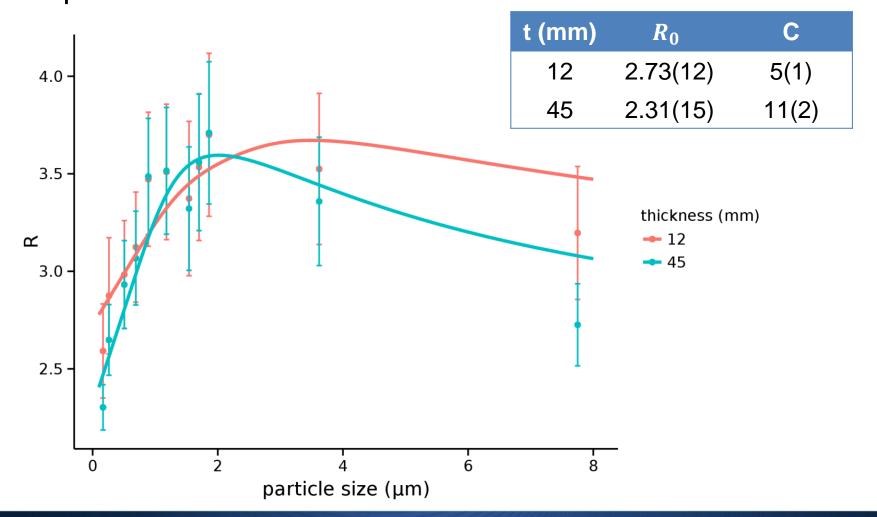
- Simulated source (SpekCalc)
- Detector efficiency and sample abs. from NIST coefficients
- Visibility as a function of energy from Thüring et al., Performance and optimization of X-ray grating interferometry, 2014





Silica microspheres 0.16 to 7.75 µm

- Fit the two parameters R₀ and C:
- Samples with two different thicknesses







Conclusions

- Good model for dark field above 50 keV on polychromatic sources
- Effective Z information is lost
- Fully complementary information on microstructures can be retrieved with R
- $R_0 > 1$ means that the phase signal is very difficult to recover





Acknowledgements

TOMCAT Team















